EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
		((test$ near memory) (BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:57
L1	871	714/733.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/24 17:23
S1	11768	test$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:02
S2	55309	test$3 with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:02
S3	36	(test$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:18
S4	8	(test$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver$5 near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 16:59
S5	0	((BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/738.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10

S6	1	((BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/733.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S7	2	(BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH) near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S8	36	(BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S9	52	((test$3 near memory) (BIST "built-in self-test" ("in circuit" near test$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:12
S10	10	("4754215", "4862460", "5214654", "5314492", "5739778").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/04/21 18:01
S11	2	"6065145".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/17 16:52

EAST Search History

S12	1256	clock near align$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/17 16:52
S13	1370	clock near align$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/17 16:52
S14	9	(clock near align$5) and (delay near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/17 16:53
S15	1987	yamada.in. and "integrated circuit"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/12/26 20:17
S16	2245	yamada.in. and "integrated circuit"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
S17	6	yamada.in. and "integrated circuit" and advantest.as.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
S18	0	(osamu and yamada).in. and "integrated circuit" and advantest. as.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
S19	38	(osamu and yamada).in. and "integrated circuit"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
S20	0	(osamu and yamada).in. and "integrated circuit" and (memory near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:19
S21	129	714/738.CCLS. and "integrated circuit" and (memory near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:19

C:\Documents and Settings\mchaudry\My Documents\EAST\Workspaces\09835170.wsp

S22	871	714/733.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:31
S23	3270	(714/733.ccls. 714/734.ccls. (built-in near test$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:32
S24	0	(714/733.ccls. 714/734.ccls. (built-in near test$3)) and (neighborhood near sensitive near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:32
S25	2	(714/733.ccls. 714/734.ccls. (built-in near test$3)) and (neighborhood near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:33
S26	24	(714/733.ccls. 714/734.ccls. (built-in near test$3)) and (sensitive near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:46
S27	4	(714/733.ccls. 714/734.ccls. (built-in near test$3)) and ((physical and logical) with (conver$5))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:46
S28	3	"6815977".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:03
S29	29	(master and slave) with (scan adj cell)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:03
S30	1187	(master and slave) with (cell)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:03
S31	21	((master and slave) with (scan adj cell)) and (scan near test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:04

S32	1914	(convert$5 with physical with logical with address)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:58
S33	2	(convert$5 with physical with logical with address) and (714/733.ccls. 714/734.ccls. (built-in near test$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:59